Technology for Optical Interconnection in LSI

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1. Research Target: Optical Switch using Ring Resonator with Electro-Optic Material

Recently the clock frequency of the micro processor is saturating because of the signal speed limit of the global metal interconnection in LSI. In order to overcome this problem we are studying optical interconnection in LSI. Our research target is to realize the compact ring-resonator optical switch using electro-optic material, which can be monolithically integrated in LSI (Fig. 1). Operation speed of the ring resonator switch is simulated to be about 100 GHz which is limited by the resonation time¹⁾ and is faster about one order of magnitude than Si optical modulator switch,²⁾ in which the switching speed is determined by the RC time constant (refer abstract of Tanushi in this proceeding). The size of the proposed ring resonator switch is very small compared with the Mach Zehnder Si modulator because the effective refractive index-change of the electro-optic material is very high compared with Si and also the ring resonator structure is used. The operation voltage is also calculated to be 1-100 V depending on the combination of the core and cladding materials. The schematic of the optically interconnected LSI is shown in Fig. 2 and the more detailed structure of the ring resonator optical switch integrated in LSI is shown in Fig. 3. Here, Pt seed layer grown by grapho $epitaxy^{3}$ on the metal interconnect layer is used to obtain a high quality electro-optic material with large electro-optic coefficient. In order to reduce the operation voltage, electro-optic material of Pb(Zr_vTi_{1-v})O₃ (PZT) with very high electro-optic coefficient is used as core material and $Pb_{1-x}La_x(Zr_vTi_{1-v})_{1-x/4}O_3$ (PLZT) is used as cladding material. The ring resonator switches should be fabricated at temperatures below 450°C because they are on the metal interconnection layer.

In this paper we report the recent research results concerning the ring resonator optical switch using electro-optic material.

2. Ring Resonator using Si Nitride

First we started to develop fabrication and measurement technologies of the ring resonator using Si nitride as a core material. Figure 4 shows the SEM image of the race-track ring resonator with Si nitride core fabricated using electron beam lithography. The Si nitride film is deposited by plasma enhanced CVD using SiH₄ and NH₃ at 350°C. The resonance characteristics is shown in Fig. 5. In the race-track resonator, the coupling efficiency between input or output waveguide and the ring is precisely controlled by the length of the straight part of the ring.⁴⁾ The gap between the waveguide and the ring is narrowed by the additional deposition of Si nitride. The resonation wavelength coincides well with the simulated value. The resonation peak is not sharp yet because the stray light from outside of the waveguide impinges into the detector.

3. Study on Electro-Optic Material

Next we studied the electro-optic material. First we employed (Ba,Sr)TiO₃ (BST) because it has been studied as high-dielectric constant material for DRAM.⁵⁾ We have fabricated Mach Zehnder interferometer as shown in Fig. 6 using spin coated BST film (0.2 µm in thickness) annealed at 500°C. However, the modulation of the output light by the applied bias is not yet achieved. The X-ray diffraction measurement indicated that the spin coated BST film is amorphous. The optical propagation loss is 2.67 dB/cm as shown in Fig.7. Recently we have fabricated poly-crystalline BST film by rf sputtering at 450°C and confirmed the output light from the waveguide. Now we are trying to realize the Mach Zehnder interferometer using the poly-crystalline After that the ring resonator switch is BST film. scheduled to be realized.

Conclusion

We have proposed the ring resonator optical switch using electro-optic material. The fabrication technology for the ring resonator with Si nitride core is developed and good resonation characteristics are observed. Concerning the electro-optic material, we employed (Ba,Sr)TiO₃ film as core material of the waveguide and confirmed the waveguide operation for the poly-crystalline BST core.

References

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Fig. 1 Ring resonator switch using electro-optic material.



Fig. 2 Optical interconnection in LSI.



Fig. 3 Detailed structure of the ring resonator optical switch. (a) Cross section. (b) Top view.



Fig. 6 Mach Zehnder interferometer. (a) Schematic. (b) Optical micrograph. (c) Cross section.



Fig. 7 Light propagation characteristics of BST waveguide.

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Plan View AI 🗘 0.8 µn

Cross Section

(b)

(c)



7. Conclusion

- Proposal of ring resonator optical switch using electro-optic material.
- Development of fabrication technology for ring resonator with Si nitride core. •Fabrication of Mach Zehnder interferometer with (Ba,Sr)TiO₃ core (electrooptic material).
- Measurement of light propagation loss of BST waveguide.